

**Search Notes**

Application/Control No.

10/672,151

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

JACOBS ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	712	5/23/2006	BT
438	723	5/23/2006	BT
438	724	5/23/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	5/23/2006	BT